



Notice of References Cited

Application/Control No.

09/830,380

Applicant(s)/Patent Under
Reexamination
ANDRE ET AL.

Examiner

Tamra L. Dicus

Art Unit

1774

Page 1 of 1

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✓	B	US-6,077,569	08-2000	Knapp et al.	427/534
	C	US-			
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office
PTO-892 (Rev. 01-2001)

Notice of References Cited

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APRIL 25, 2001

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W. A. H. H.

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INFORMATION DISCLOSURE CITATION

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